

Certified Reference Material

Certificate of Analysis

Product ID: IARM-Cu101-18

ISO 17034:2016 ISO/IEC 17025:2017 ISO 9001:2015

Product Description: Copper Alloy, CDA 101 / UNS C10100

Revision No.: 000
Revision Date: 04/06/2022

Description and Intended Use: This **Certified Reference Material** is covered under the scope of accreditation to **ISO 17034** by LGC Standards - Manchester, NH. As an ISO 17034 certified reference material, appropriate use of this material will fulfill the certified reference material and traceability requirements for use in **ISO 17025** accredited laboratories. This CRM may come in the form of a solid disk, or chips. The intended use of this CRM may include, but is not limited to, the calibration of instruments and the validation of analytical methods.

Certified Values listed in ppm with associated uncertainties

Ag	13.0	± 3.0	As	1.5	± 0.6	Bi	0.5	± 0.3	Fe	3.0	± 2.0
Mn	0.3	± 0.1	Ni	2.7	± 0.8	Pb	1.2	± 0.9	S	5.0	± 2.0
Sb	1.4	± 0.8	Sn	2.0	± 1.0	Zn	0.8	± 0.5			

Indicative Values listed in ppm

Al (1)	C (10)	Cd (0.7)	Co (0.3)	Cr (0.5)	Cu (99.93%)	Mg (0.6)
N (1)	O (2)	P (4)	Se (2)	Si (3)	Te (10)	

Homogeneity and Uncertainty: "Uncertainty" values, as reported adjacent to certified concentration values, are based on a 95% Confidence Interval. These estimated uncertainties include the combined effects of method imprecision, material inhomogeneity, and any bias between methods. Homogeneity data from experimental XRF results are reflected in both the overall statistics and certified data. Homogeneity samples are selected by a systematic sampling procedure. The number of samples may be determined by equation 1, where N_{prod} is the number of units produced and N_{min} is the number of samples used for homogeneity testing. These samples are arranged in a simple randomized design such that each sample is analyzed multiple times by XRF. Homogeneity may also be determined within sample using an applied version of ASTM E826. A single factor ANOVA is used to calculate uncertainty due to inhomogeneity (U_{hom}). Uncertainty of the material is calculated by equation 2, where $H=U_{hom}$, S = Standard deviation, t = t-value at 95% CI, and n = number of observations.

$$1. N_{MIN} = \max(10, \sqrt[3]{N_{PROD}}) \qquad 2. U_{CRM} = \frac{\sqrt{H^2 + S^2}}{\sqrt{n}} * t$$

Certification Laboratories: Much of the analytical work performed to assess this material has been carried out by laboratories with proven competence, as indicated by their accreditation to ISO 17025. It is an implicit requirement for this accreditation that analytical work should be performed with due traceability, via an unbroken chain of comparisons, each with stated uncertainty, to primary standards such as the mole, or to nationally- or internationally-recognized reference materials. Of the individual results herein, some have traceability (to the mole) via primary analytical methods. Some are traceable to substances of known stoichiometry. Most have traceability via commercial solutions. Furthermore, some results have additional traceability to NIST standards, as part of the analytical calibration or process control.

- LGC Standards - Manchester, NH
- Connecticut Metallurgical, Inc. - East Hartford, CT
- Dirats Laboratories - Westfield, MA
- Laboratory Testing, Inc. - Hatfield, PA
- Northern Analytical Laboratory, Inc. - Londonderry, NH
- NSL Analytical Services - Cleveland, OH
- EAG Laboratories - Liverpool, NY
- Lucid Laboratories - Telangana, India
- National Research Council Canada - Ottawa, Canada
- Scrooby's Laboratory Service - Benoni, South Africa
- Sheffield Analytical Services - Sheffield, UK
- TEC Eurolab - Campogalliano, Italy
- Universal Scientific Laboratory - Revesby, Australia
- Lithea s.r.o. - Brno, Czech Republic

Instructions for Use: The test surface is on the opposite side of the labeled surface, which includes the material identification. The entire thickness of the unit is certified. However, the user is cautioned not to measure disks less than 2 mm thick when using X-ray fluorescence spectrometry. Each packaged disk has been prepared by finishing the test surface using a lathe. The user must determine the correct surface preparation procedure for each analytical technique. The user is cautioned to use care when either resurfacing the disk or performing additional polishing, as these processes may contaminate the surface. The minimum sample size for chips should be individually evaluated based on the analytical technique used; this would typically be greater than 0.1 grams. The material should be stored in a cool, dry location when not in use.

Chips are not recommended for gas analysis.

Period of Validity: The certification of this material is valid indefinitely, within the uncertainty specified, provided the material is handled and stored in accordance with the instructions stated on this certificate. The certification is nullified if the material is damaged, contaminated, otherwise modified, or used in a manner for which it was not intended.


Kimberly Halkotis, Global Product Manager

April 06, 2022
Certification Date



ISO 17034 Accredited: Reference Materials
Producer, Certificate # 2848.02
ISO/IEC 17025 Accredited: Chemical
Testing, Certificate # 2848.01

Conditions of Sale and Supply: All CRMs & RMs sold are subject to applicable LGC Standard Terms and Conditions of Sale.

The following data represents all pertinent information reported as it applies to the chemical characterization of this material.

	Ag	Al	As	Bi	C	Cd	Co	Cr	Cu (wt. %)	Fe	Mg	Mn
1	7.0000	0.0030	0.7000	0.1800	1.3000	0.1000	0.0040	0.0300	99.900	0.2000	0.0100	0.1600
2	8.8000	0.0090	0.7500	0.2000	22.900	0.9000	0.0100	0.0500	99.900	1.3000	0.0100	0.2000
3	10.000	0.0120	1.0000	0.2600		1.0000	0.1000	0.1600	99.900	1.4000	0.2600	0.2400
4	10.000	0.9000	1.0000	0.2800		<0.0008	0.4000	0.8000	99.980	1.8000	0.6000	0.2500
5	10.000	1.0000	1.1000	0.5000		<0.05	1.1000	1.3000	99.990	2.0000	1.2000	0.3000
6	10.000	1.0000	1.2000	1.0000		<0.1	<0.01			2.4000	1.6000	0.5000
7	10.300	1.8000	1.2000	1.0000		<0.5	<0.1			2.5000	<0.05	<1
8	11.000	1.9000	2.0000	<1		<1	<1			5.4000	<1	<1
9	11.000	3.5000	2.3000	<10		<1	<1			6.0000	<1	<2
10	11.200	<1	3.4000	<20		<2	<1			8.1000	<2	<5
11	15.600	<1	<0.6	<20		<5	<2			<1	<5	<10
12	19.000	<5	<5	<20		<10	<5			<10	<10	<20
13	19.000	<10	<20	<20		<20	<10			<20	<20	<20
14	23.000	<20	<20			<20	<20			<20	<20	<20
15	<1	<20	<20				<20			<20	<100	
16	<5	<20	<50									
17												
Mean	12.564	1.1249	1.4650	0.4886	12.100	0.6667	0.3228	0.4680	99.934	3.1100	0.6133	0.2750
STDV	4.6762	1.1468	0.8518	0.3646	15.274	0.4933	0.4634	0.5621	0.0467	2.5164	0.6589	0.1200
Certified	13.0	(1)	1.5	0.5	(10)	(0.7)	(0.3)	(0.5)	(99.93%)	3.0	(0.6)	0.3
U _{CRM}	3.0		0.6	0.3						2.0		0.1
Methods	I,IM,G,X	I,IM,G,O,X	I,IM,G,O,X	I,G,IM,O,X	C,G	I,G,IM,X	I,G,IM,X	G,I	I,W,O,X	I,G,IM,O,X	I,G,IM,O,X	I,G,IM,O,X

	N	Ni	O	P	Pb	S	Sb	Se	Si	Sn	Te	Zn
1	1.4000	1.2000	2.1000	0.1100	0.6000	2.1000	0.5000	0.1000	0.0500	0.1000	0.0800	0.1000
2	<5	1.7000	<5	0.2000	0.6000	2.8000	0.6000	0.1500	0.0600	0.1700	0.2500	0.1700
3		2.0000		0.2900	0.9600	3.6000	0.6000	2.0000	0.0600	0.4600	3.6000	0.2500
4		2.0000		0.3000	1.0000	4.0000	0.6900	2.6000	0.1000	1.0000	5.3000	0.6200
5		2.0000		0.5400	1.0000	5.0000	0.7100	3.9000	4.5000	1.1000	12.000	1.0000
6		2.1000		1.0000	1.1000	5.1000	0.9000	4.6000	8.0000	1.5000	20.000	1.0000
7		2.7000		6.3000	1.2000	5.8000	1.0000	<0.1	10.000	3.0000	21.000	1.1000
8		3.3000		9.0000	1.8000	7.0000	2.0000	<0.5	<1	3.7000	24.000	2.0000
9		3.8000		12.000	2.7000	7.2000	2.9000	<1	<2	4.0000	24.000	<1
10		4.0000		13.800	<5	10.000	3.7000	<1	<5	<0.5	<0.07	<1
11		4.4000		<1	<10	<10	<2	<5	<20	<1	<0.1	<5
12		<1		<5	<10	<10	<5	<20	<20	<1	<1	<20
13		<5		<20	<20	<10	<10	<20	<20	<6	<5	<20
14		<10		<20	<20	<20	<10	<20	<25	<10	<10	<20
15		<20		<50	<20	<20	<20	<50	<50	<20		
16		<20			<20	<20	<20			<20		
17		<20				<20				<20		
Mean	1.4000	2.6545	2.1000	4.3540	1.2178	5.2600	1.3600	2.2250	3.2529	1.6700	12.248	0.7800
STDV		1.0586		5.4475	0.6590	2.3576	1.1237	1.8686	4.2857	1.5125	10.174	0.6357
Certified	(1)	2.7	(2)	(4)	1.2	5.0	1.4	(2)	(3)	2.0	(10)	0.8
U _{CRM}		0.7			0.5	2.0	0.8			1.0		0.5
Methods	F,G	I,IM,G,O,X	F,G	I,G,IM,X,W	I,IM,G,O,X	C,I,G,O,X	I,IM,G,O,X	I,G,IM,X	G,I,IM,O,X,W	I,IM,G,O,X	G,I,IM,O,X	I,G,IM,O,X

Legend: W = Classical, C = Combustion, F = Fusion, A = AA or GFAA, I = ICP or DCP, IM=ICP-MS, D = DC Arc, O = AES, X = XRF, G = GDAES or GDMS, H = Hollow Cathode AES

The following data was analyzed by GDMS and is intended for informational purposes only. All values listed in ppm.

	Au	B	Ba	Be	Br	Ca	Ce	Cl	Cs	Dy	Er	Eu	F	Ga
1	<0.05	<0.0008	<0.0003	<0.0004	<<0.02	<<0.01	<<0.0003	0.01	<0.0005	<0.005	<0.005	<0.005	0.01	<0.003
2	<0.1	<0.005	<0.005	<0.005	<0.05	<0.01	<0.005	0.05	<0.005	<0.05	<0.05	<0.05	<0.05	<0.01
3	<0.1	0.010000	<0.05	<0.01	<0.1	<0.1	<0.05	<0.01	<0.05				<0.1	<0.1

	Gd	Ge	Hf	Hg	Ho	I	In	Ir	K	La	Li	Lu	Mo
1	<0.005	<0.004	<0.0009	<0.01	<0.005	0.005	<0.0002	<0.005	0.04	<0.0002	<0.0004	<0.005	<0.002
2	<0.05	<0.005	<0.005	<0.01	<0.05	<0.005	<0.005	<0.1	<0.001	<0.005	<0.005	<0.05	<0.005
3		<0.05	<0.05	<0.5		<0.05	<0.1		<0.1	<0.05	<0.01		<0.1

	Na	Nb	Nd	Os	Pd	Pr	Pt	Rb	Re	Rh	Ru	Sc	Sm
1	0.05	<0.003	<0.005	<0.005	<0.05	<0.005	<0.009	<0.0006	<0.005	<0.05	<0.005	<0.0004	<0.005
2	<0.001	<0.005	<0.05	<0.1	<0.1	<0.05	<0.05	<0.005	<0.05	1.000000	<0.1	<0.005	<0.05
3	<0.01	<0.05					<0.1	<0.05				<0.05	

	Sr	Ta	Tb	Th	Ti	Tl	Tm	U	V	W	Y	Yb	Zr
1	<0.0005	<0.1	<0.005	<0.0003	<0.0003	<0.003	<0.005	<0.0003	<0.0003	<0.001	<0.0004	<0.005	<0.0004
2	<0.005	<0.5	<0.05	<0.005	<0.005	<0.005	<0.05	<0.005	<0.005	<0.05	<0.005	<0.05	<0.005
3	<0.05			<0.01	<0.01	<0.05		<0.01	<0.01	<0.1	<0.05		<0.05